

FAST - [default.wsp:1]

File View Edit Tools Window Help

Active

- L1: (47) CoFe near3 ferromagnetic and (spin near2 valve or AMR)
- L5: (49) CoFe near5 ferromagnetic and magnetoresist3
- L6: (21) 5 not 1
- L7: (99) CoFe same ferromagnetic and magnetoresist3
- L8: (50) 7 not 5
- L9: (71) 7 not 1
- L10: (50) 8 not 1

Search: [] [] [] [] [] []

DBs: USPAT; US-PGPUB; JPO; IBM TDB

Default operator: OR

☒ Plurals ☐ Synonyms

☒ Highlight all hit terms initially

BRS term E&R term Image Text

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error
1	BRS	L1	47	CoFe near3 ferromagnetic and (spin near2 valve or AMR)	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:18		
2	BRS	L5	49	CoFe near5 ferromagnetic and magnetoresist3	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:20		
3	BRS	L6	21	5 not 1	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:19		
4	BRS	L7	99	CoFe same ferromagnetic and magnetoresist3	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:23		
5	BRS	L8	50	7 not 5	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:20		
6	BRS	L9	71	7 not 1	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:21		
7	BRS	L10	50	8 not 1	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:21		
8	BRS	L11	128	(CoFe or FeCo) same ferromagnetic and magnetoresist3	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:23		
9	BRS	L12	29	11 not 7	USPAT; US-PGPUB; JPO; IBM TDB	2001/12/13 09:23		

Ready

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ferromagnetic coupling of the two ferromagnetic layers 12, 16 through the layer 14 of nonmagnetic metallic material. Centering the response to zero field, as shown in the dashed line in FIG. 6, can be accomplished by several means. In an actual patterned structure, the magnetostatic interaction between the two ferromagnetic layers would tend to cancel the effect of coupling through the nonmagnetic metallic layer thereby centering the response. Another way of centering the response is by the appropriate choice of the magnitude and direction of the sense current. Another way of centering the response is by setting the easy axis of layer 12 at slightly more than 90 degrees with respect to the magnetization of layer 16. A further way of centering the response is by a small change in the angle between the magnetization in layers 12 and 16. Note that this response is very linear, is centered at zero field, and is sensitive to signals within the range encountered in magnetic recording applications. It can be seen that these characteristics make this an excellent magnetic field sensor for magnetic recording application.

DEPR:

The ferromagnetic layers 12, 16 can be made of any suitable magnetic materials such as Co, Fe, Ni and their alloys such as NiFe, NiCo, and FeCo, for example. The amplitude of the magnetoresistance varies with the thickness of the first thin film ferromagnetic layer 12 as shown in FIG. 7 for three selected magnetic materials Co, NiFe, and Ni. These three curves have very similar shapes characterized by a broad maximum between about 50.ÅNG. and 150.ÅNG., so this is the preferred range for the thickness of the first ferromagnetic layer 12.

CLPR:

1. The magnetoresistive sensor comprising:

CLPR:

2. A magnetoresistive sensor comprising:

CLPR:

3. The magnetoresistive sensor of claim 1 wherein said means for fixing the magnetization direction of said second layer of ferromagnetic material comprises providing said second layer of ferromagnetic material with a substantially higher coercivity than the coercivity of said first layer of ferromagnetic material.

CLPR:

4. The magnetoresistive sensor of claim 1 wherein said means for fixing the magnetization direction of said second layer of ferromagnetic material

Patent Number: 5,106,590
Date of Patent: Apr. 27, 1993

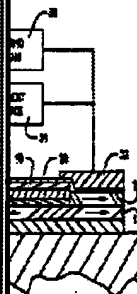
Shenoy, G. Shankar, et al., *IEEE Trans. on Magn.* 29, 4019 (1993).
"Thin Film Magnetoresistive Memory, Sensors, and Related Applications", D. A. Thompson, et al., *IEEE Trans. Mag.*, p. 1022, (1992).

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Attorney, Agent, or Firm—Owen, Schmitt, Jr., Leslie G. Murray

ABSTRACT

A magnetoresistive (MR) sensor comprising a first and a second thin film layer of a magnetic material separated by a thin film layer of a non-magnetic metallic material. The first ferromagnetic layer is magnetically soft. The magnetization direction of the first layer of magnetic material is set substantially perpendicular to the magnetization of the second layer of magnetic material at zero applied field, and the magnetization direction of the second layer of magnetic material is fixed. A current I_{sense} is produced through the MR sensor, and the voltage V across the MR sensor is measured due to change in resistance of the MR sensor produced by rotation of the magnetization in the thin layer of magnetic material as a function of the magnetic field being sensed. The variation of the resistance with the angle between the magnetizations of the first and second layers of magnetic material has been defined as the spin valve (SV) effect. It is also known that, by a suitable direction of the current with respect to the fixed magnetization, the (SV) magnetoresistance can be added constructively to the usual anisotropic magnetoresistance.

FIG. 6, FIG. 7



magnetoresistive response for a prior art spin valve MR sensor structure;

DEPR:

FIG. 5 is a graph illustrating the magnetoresistive response for the MR sensor shown in FIG. 2;

DEPR:

FIG. 9 is an exploded view in perspective of another preferred embodiment of the magnetoresistive sensor according to the principles of the present invention; and

DEPR:

FIG. 10 is an end view of another embodiment of a magnetoresistive sensor constructed in accordance with the present invention.

DEPR:

According to this preferred embodiment of the present invention, the ferromagnetic layers 31, 35 and 39 can be fabricated of any suitable magnetic material such as cobalt (Co), iron (Fe), nickel (Ni) and their alloys such as nickel-iron (NiFe), nickel-cobalt (NiCo) and iron-cobalt (FeCo), for example. The non-magnetic metallic spacer layers 33 and 37 comprise copper (Cu), for example, or other suitable noble metal such as silver (Ag) or gold (Au) or their alloys. An MR sensor based on the spin valve effect wherein the sensor read elements comprises a ferromagnetic/non-magnetic/ferromagnetic layered structure is described in greater detail in the above referenced patent no. 5,206,590 hereby incorporated by reference as if fully set forth herein. The fixed or pinned outer ferromagnetic layers 31 and 39 can be exchange biased by adjacent layers (as shown in FIG. 9) of an antiferromagnetic material such as iron-manganese (FeMn), for example. An MR sensor based on the spin valve effect wherein a pinned ferromagnetic layer is exchange biased by an adjacent antiferromagnetic layer is described in greater detail in the above referenced patent application Ser. No. 07/937,620 hereby incorporated by reference as if fully set forth herein. Alternatively, the magnetization directions of the pinned ferromagnetic layers 31, 39 can be fixed by use of an adjacent hard magnetic layer or by use of a material having a sufficiently high coercivity for the outer pinned layers 31, 39.

DEPR:

The structure of a conventional or single spin valve MR sensor as described in the above-cited patent applications is essentially FM.sub.free

/PM/PM sub pinned /AFM where PM sub free and PM sub pinned are ferromagnetic

US 5,207,238 A
(1) Patent Number 5,207,238
(4) Date of Patent Feb. 15, 1994

OTHER PUBLICATIONS

"Giant MR: A Primer", *WIRE*, IEEE Trans. on Magnetics, vol. 28, No. 1, Sep. 1992, pp. 1463-1464.
Tsunagawa, "The Film Magnetoresistivity in Manganese, Iron, and Nickel Alloys", *IEEE Trans. on Magnetics*, vol. 28, No. 6, pp. 1579-1582.

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Assistant, Agent, or Prior—Linda G. Murray

ABSTRACT

A magnetoresistive read sensor based on the spin valve effect and having a multilayered read spin valve structure is disclosed. The sensor read element includes first, second and third layers of ferromagnetic material separated from each other by layers of non-magnetic metallic material. The first and third layers of ferromagnetic material, i.e., the outer layers of the structure, have their magnetization orientation fixed, while the second, intermediate ferromagnetic layer is magnetically soft and has its magnetization oriented perpendicular to that of both the outer ferromagnetic layers in the absence of an applied magnetic field. In one preferred embodiment, the two outer ferromagnetic layers have their magnetization fixed in such a way by exchange coupling with adjacent antiferromagnetic layers.

FIG. 7 Drawing Sheet

